

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application No.	10/590,046
		Filing Date	June 15, 2007
		First Named Inventor	Hirayama et al.
		Art Unit	1795
(Multiple sheets used when necessary)		Examiner	Johnson, C.
SHEET 1 OF 3		Attorney Docket No.	SHIGA7.055APC

U.S. PATENT DOCUMENTS					
Examiner Initials	Cite No.	Document Number <i>Number - Kind Code (if known)</i> Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	5,693,452	12-02-1997	Aoai et al.	
	2	6,037,098	03-14-2000	Aoai et al.	
	3	6,106,993	08-22-2000	Watanabe et al.	
	4	7,504,196	03-2009	Shiono et al.	
	5	2002/0025495	02-28-2002	Ogata et al.	
	6	2008/0259273	11-08-2007	Shiono et al.	
	7	2009/0162781	06-2009	Shiono et al.	

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document <i>Country Code-Number-Kind Code</i> Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	8	JP 2000-086584	03-28-2000	Honshu Chemical Ind Co Ltd		Abstract
	9	JP 2000-330282	11-30-2000	Nagase Densi Kagaku KK.		✓
	10	JP 2003-260881	09-16-2003	Fuji Photo Film		✓
	11	JP 2003-030282	01-31-2003	NEC Corp		Abstract
	12	JP 2004-302440	10-28-2004	JSR Corp		Abstract
	13	JP 2004-359590	12-24-2004	JSR Corp		Abstract
	14	JP H06-059444	03-04-1994	Japan Synthetic Rubber Co Ltd.		Abstract
	15	JP H08-337616	12-24-1996	Shin Etsu Chem. Co. Ltd.		Abstract
	16	JP H09-211866	08-15-1997	Shin Etsu Chem Co Ltd		Abstract
	17	JP H10-123703	05-15-1998	Fuji Photo Film Co Ltd		
	18	JP H10-274845	10-13-1998	Fuji Photo Film Co Ltd		Abstract
	19	JP H11-167199	06-22-1999	Fuji Photo Film Co Ltd		✓
	20	JP H11-199533	07-27-1999	Honshu Chemical Ind Co Ltd		Abstract
	21	KR 0231242	05-30-1997	Watanabe et al.		
	22	KR 2001-0088341	09-26-2001	Fuji Photo Film Co., Ltd.		Abstract
	23	KR 406242	11-06-2003	Aoai et al.		

Examiner Signature	Date Considered
<p>*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	

¹ - Place a check mark in this area when an English language Translation is attached.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application No.	10/590,046
		Filing Date	June 15, 2007
		First Named Inventor	Hirayama et al.
		Art Unit	1795
(Multiple sheets used when necessary)		Examiner	Johnson, C.
SHEET 2 OF 3		Attorney Docket No.	SHIGA7.055APC

FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	24	TW 200617602	06-01-2006	Tokyo Ohka Kogyo Co., Ltd.		Abstract
	25	WO 2006/046383	05-2006	Shiono et al.		

NON PATENT LITERATURE DOCUMENTS						
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ¹
	26	HIRAYAMA et al. "Development of Electron Beam Resists Based on Amorphous Polyphenols with Low Molecular Weight and Narrow Dispersion" Proceedings of SPIE Vol. 5753, pg. 738-745.				
	27	HIRAYAMA et al., Journal of Photopolymer Science and Technology, Vol. 17, No. 3, 435-440, (2004)				
	28	Hirayama, T., et al. "Depth Profile and Line-Edge Roughness of Low-Molecular-Weight Amorphous Electron Beam Resists", The Japan Journal of Applied Physics, Vol. 44, No. 7B, 2005, pp. 5484-5488.				
	29	International Search Report dated September 6, 2005 for PCT/JP2005/013564.				
	30	International Search Report from PCT/JP2005/018143 dated November 15, 2005.				
	31	International Search Report from PCT/JP2006/302271, mailed on March 7, 2006				
	32	International Search Report in connection with corresponding PCT application no. PCT/JP2006/313103, dated September 26, 2006.				
	33	International Search Report issued in corresponding PCT Application No. PCT/JP2006/311443, dated June 7, 2006				
	34	International Search Report, PCT/JP2006/301679, February 16, 2006.				
	35	Office Action issued September 16, 2008 on the counterpart Korean Patent Application No. 10-2007-7010473.				
	36	Notice of Allowance issued on related Korean Patent Application No. 10-2009-7006750, dated February 16, 2010.				
	37	Office Action issued in counterpart Japanese Patent Application No. 2005-026266, dated March 3, 2009.				
	38	Office Action issued in counterpart Japanese Patent Application No. JP 2005-050721, dated July 28, 2009.				
	39	Office Action issued in counterpart Japanese Patent Application No. JP 2005-050721, dated March 3, 2009.				
	40	Office Action issued in counterpart Korean Patent Application No. 10-2007-7017441, dated May 7, 2009				
	41	Office Action issued in Korean Patent Application No. 10-2007-7004390, dated December 17, 2008.				

Examiner Signature	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

¹ - Place a check mark in this area when an English language Translation is attached.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Application No.	10/590,046
		Filing Date	June 15, 2007
		First Named Inventor	Hirayama et al.
		Art Unit	1795
<i>(Multiple sheets used when necessary)</i>		Examiner	Johnson, C.
SHEET 3 OF 3		Attorney Docket No.	SHIGA7.055APC

	42	Office Action issued in Korean Patent Application No. 10-2008-7025851, dated January 7, 2009.	
	43	Office Action issued on April 14, 2008 on the counterpart Korean Patent Application No. 10-2007-7004390.	
	44	Office Action issued on the counterpart Korean Patent Application No. 10-2007-7019433, dated June 5, 2008.	

8804253
033010

Examiner Signature	Date Considered
*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

T¹ - Place a check mark in this area when an English language Translation is attached.